
FTI STUDIO™ YIELD MONITOR MANUAL

Copyright © 2007 Focused Test Inc

Table of Contents

Overview	3
Monitor Setup	3
Yield Monitor Panel Configuration Options	4
Item	4
Num	4
Condition	5
Value	5
Action	6
Actual Value	6
Skip N Devices	6
Average N Devices	6
Adding New Criteria	7
Save/Load Monitor Setup	8
Yield Monitor – Warning	9
Yield Monitor – Error	10

OVERVIEW

The Yield Monitor subsystem provides a built-in out-of-control alerting mechanism in the FTI Studio environment.

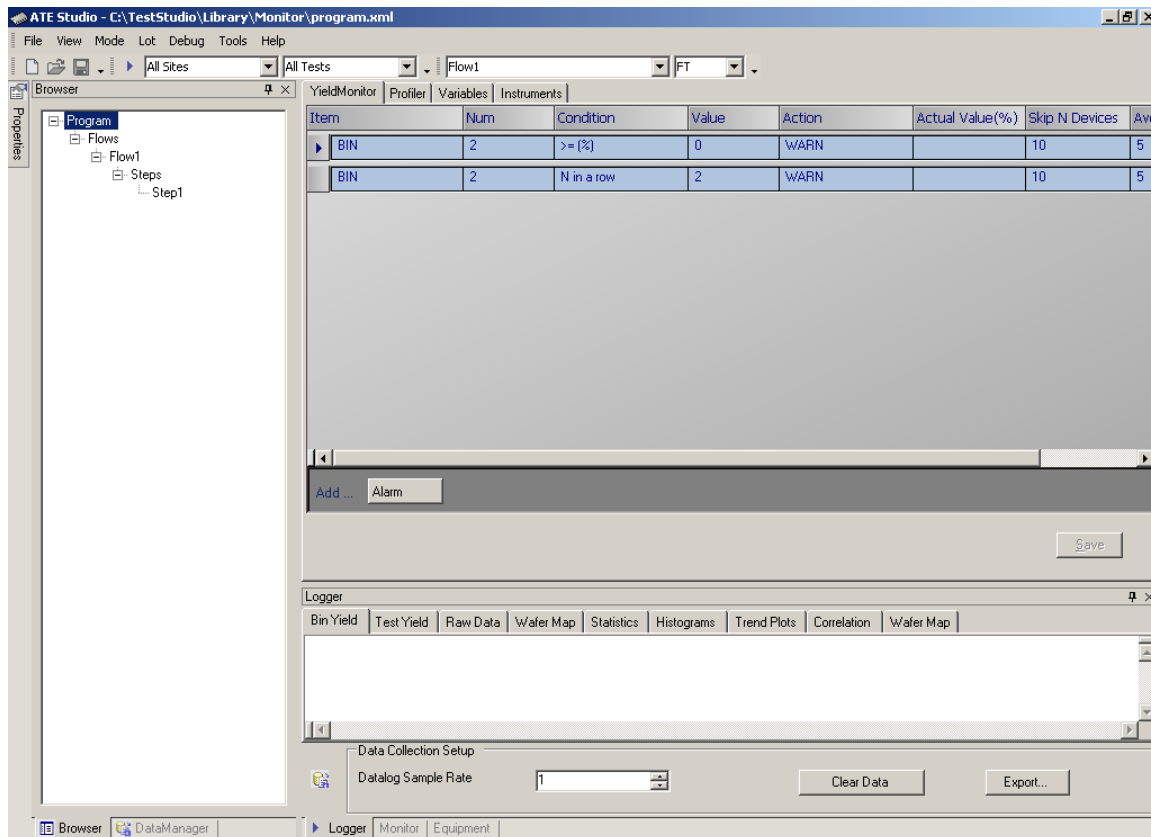
This subsystem checks for user-defined “alarm” conditions, on bin yields and test yields.

Whenever the condition is violated, the subsystem warns or stops testing based on the monitor configuration.

MONITOR SETUP

The Yield Monitor subsystem is part of the program environment.

The screen given below displays the Yield Monitor setup GUI.



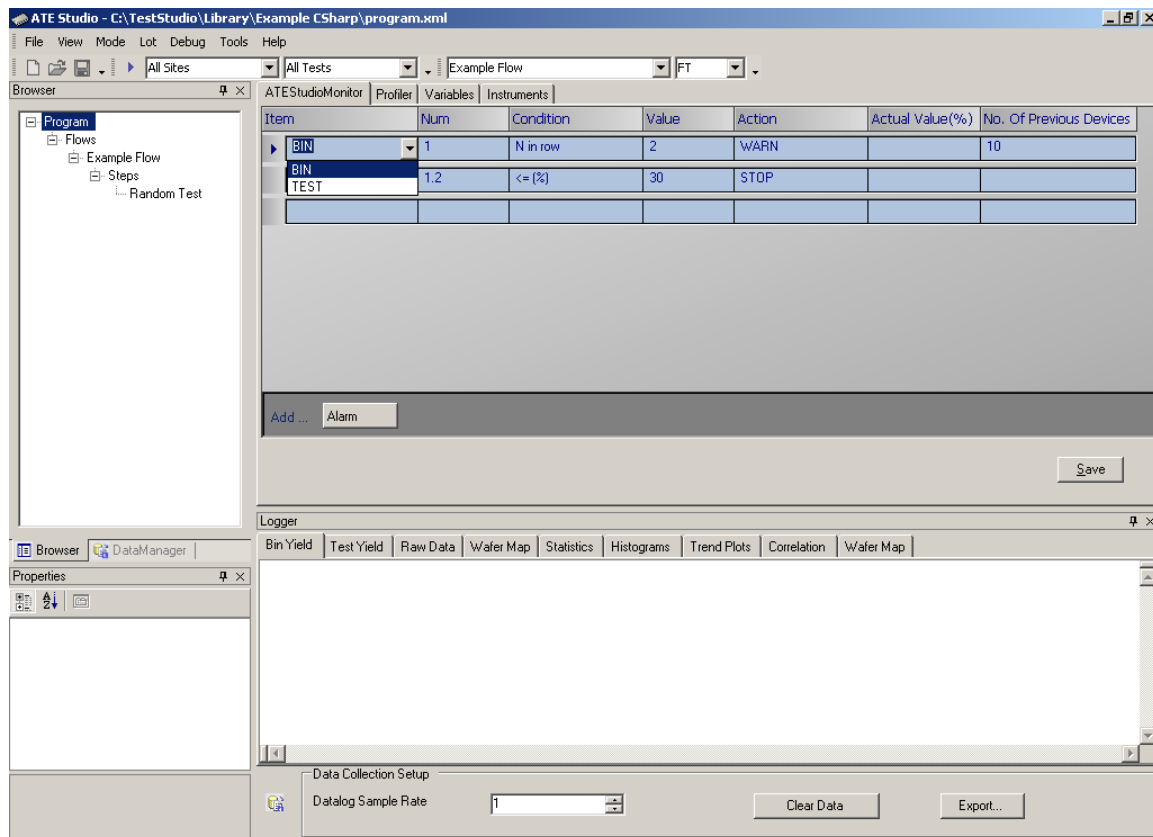
The Yield Monitor panel allows the user to setup the bin/test yield monitoring criteria.

YIELD MONITOR PANEL CONFIGURATION OPTIONS

The user can setup the following options

ITEM

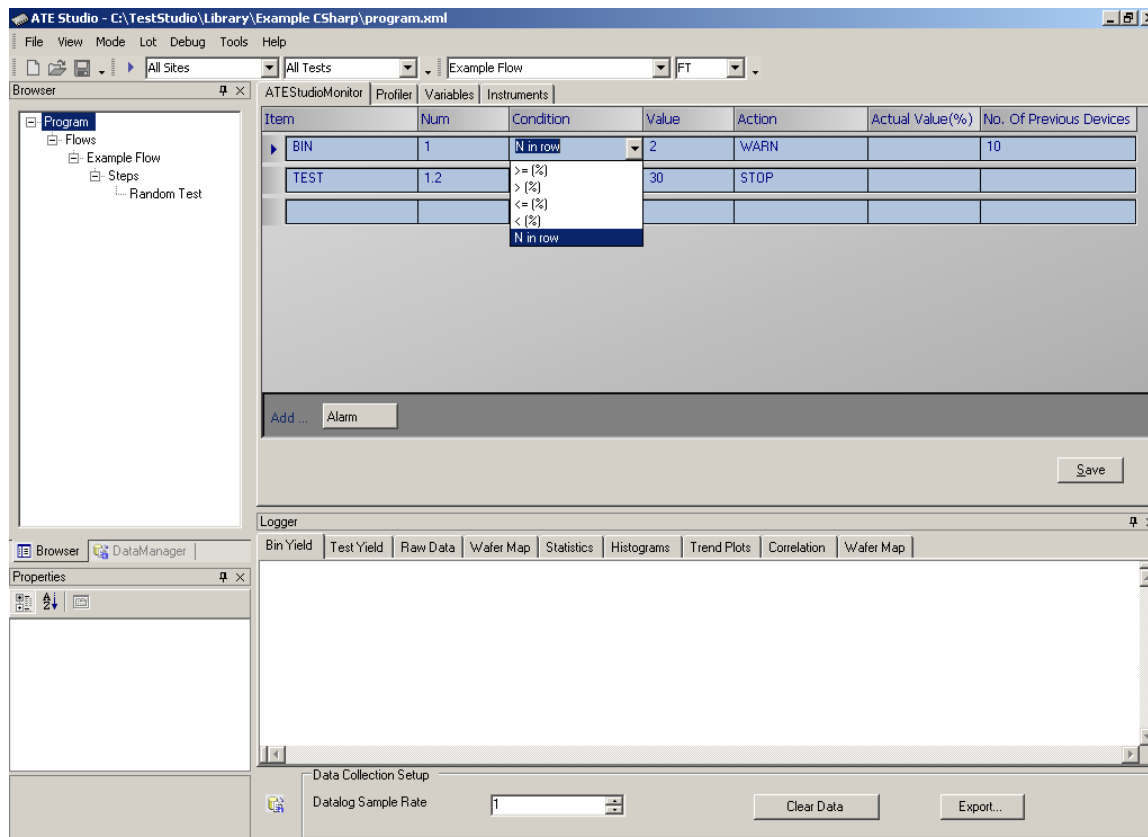
This can be BIN/TEST. Choose BIN for BIN related criteria. TEST for test related criteria.



NUM

Denotes the bin number or test number that needs to be monitored. You can also enter sub-test number.

CONDITION



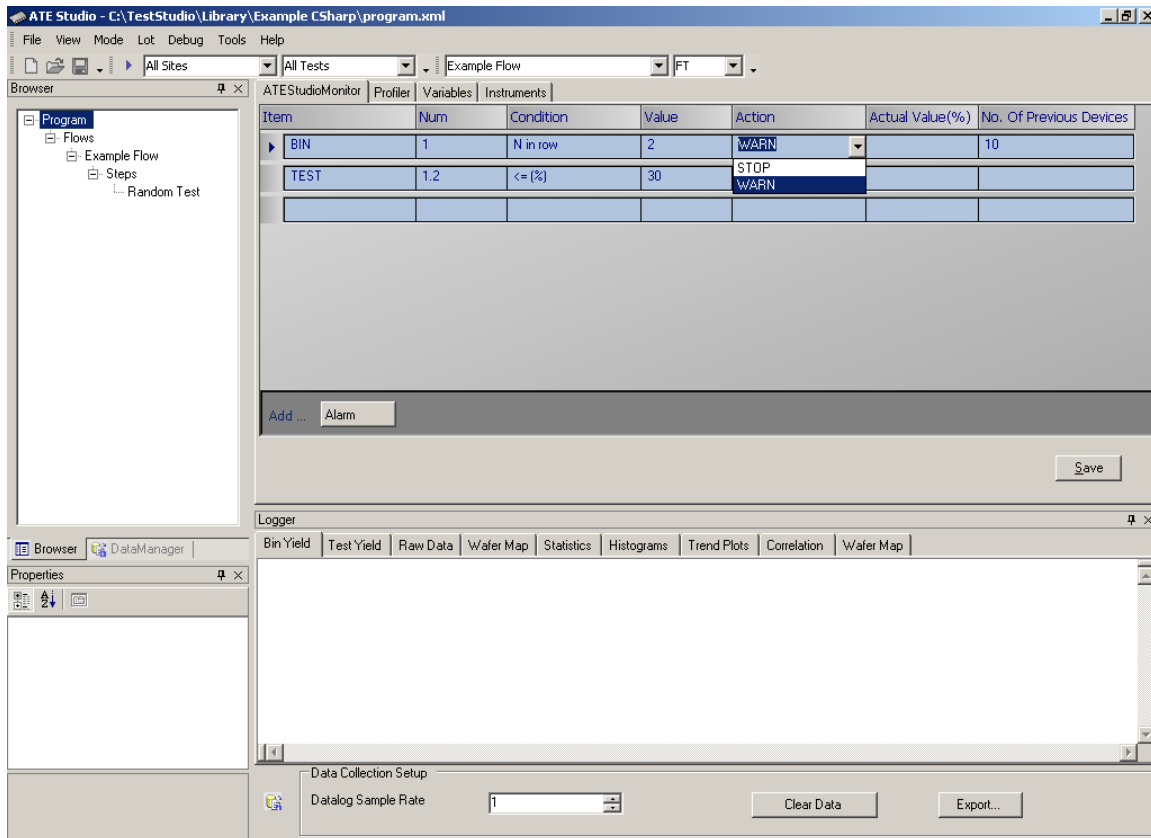
- The Yield Monitor supports conditions on bin/test yield percentages. You can configure to compare the bin/test yields for a specific bin/test against a predefined value. The various conditions supported are <, >, <=, >=.
- It also supports a special condition, N in row. This criteria is applied when a particular bin number occurs in a row for a defined number of times.

VALUE

Refers to the bin/test yield percentage value to compare against. In case of N in row condition, this value refers to the number of times a particular bin number occurs.

ACTION

You can choose to either WARN or STOP testing. WARN would highlight the failed criteria. The testing will still continue. STOP will also highlight the failed criteria and this will STOP testing. STOP is useful for critical error conditions.



ACTUAL VALUE

This column will contain the actual yield value when the specific criteria failed.

SKIP N DEVICES

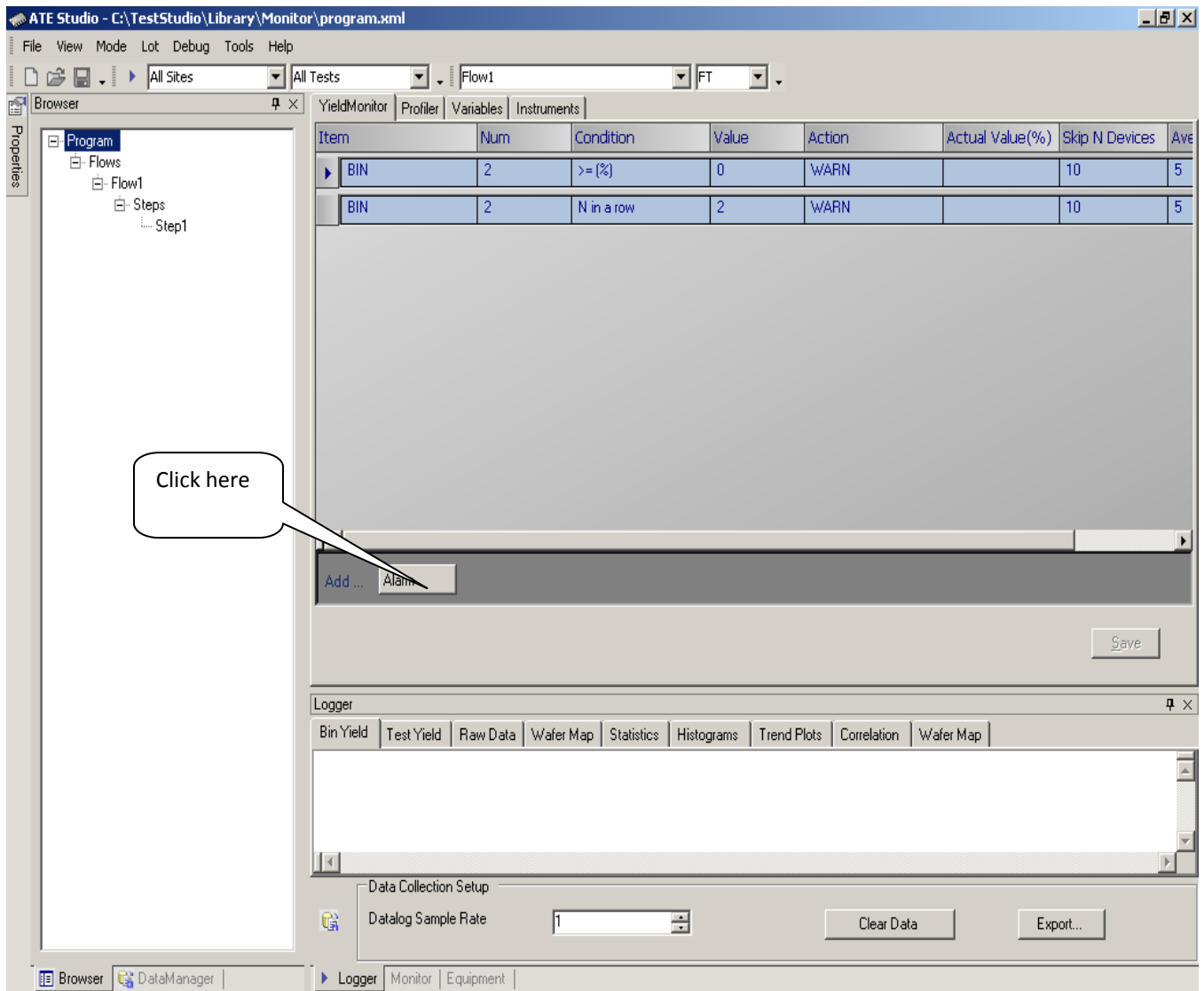
When this value is set, yield monitor will wait for the given number of devices to be tested before the yield criteria is applied.

AVERAGE N DEVICES

This value indicates the number of devices that should be cached in the monitor device queue, to calculate the running average yield.

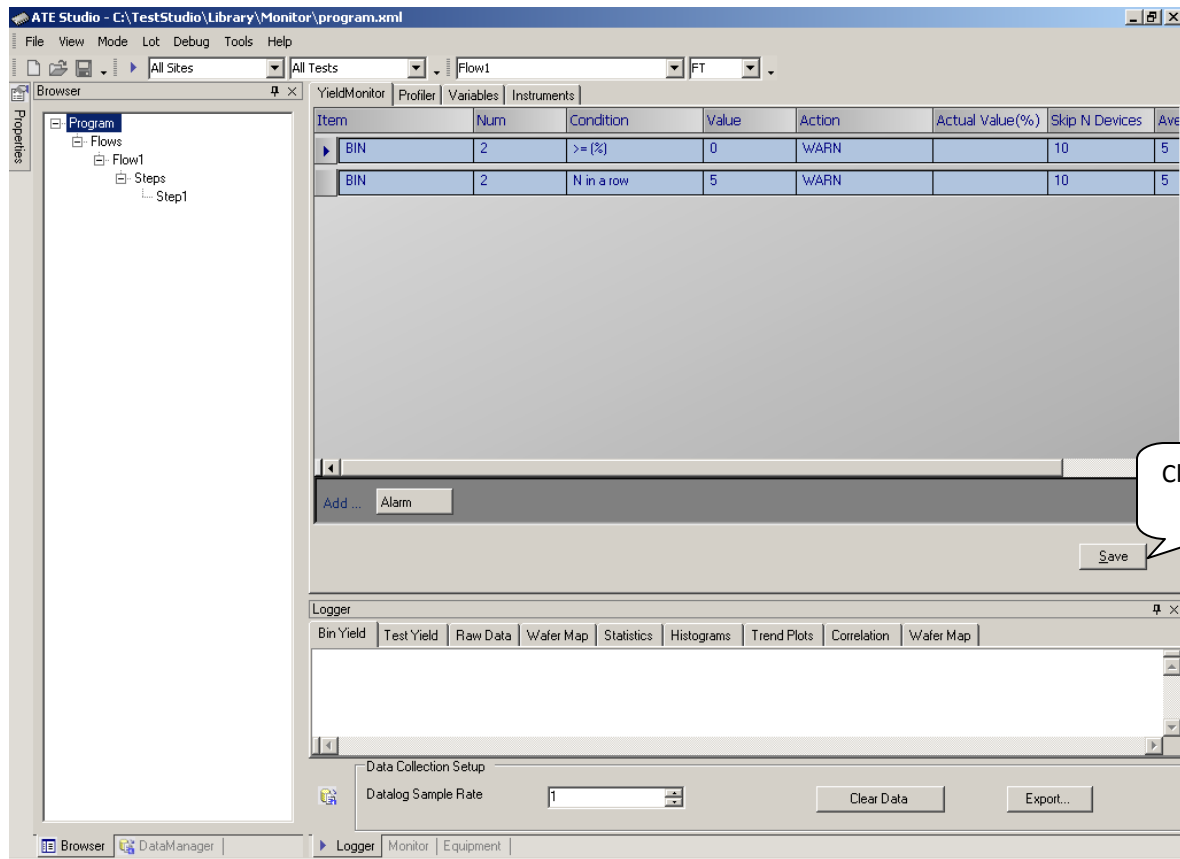
ADDING NEW CRITERIA

Press on the Alarm button to add new criteria.



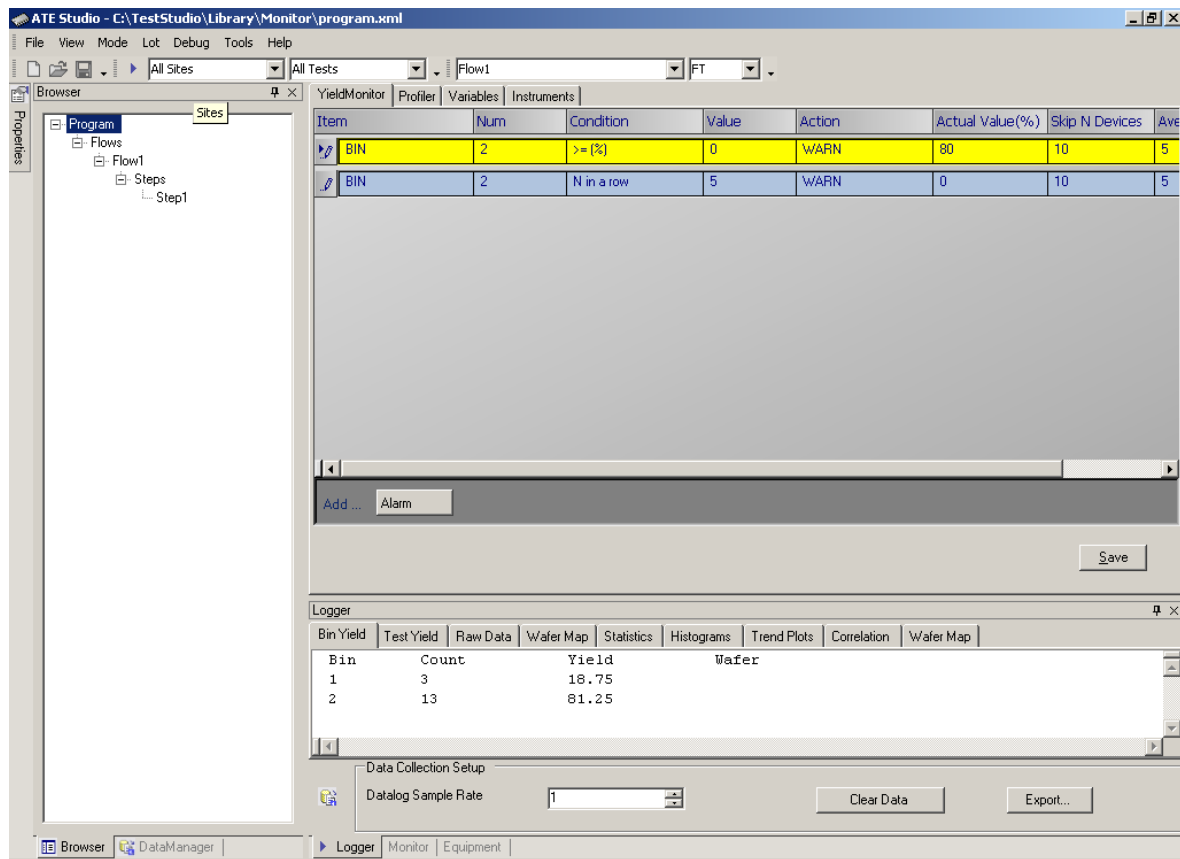
SAVE/LOAD MONITOR SETUP

Click on the save button to save Monitor setup. The setup will be saved alongwith the program information. FTI Studio will load this setup whenever it loads the program.



YIELD MONITOR – WARNING

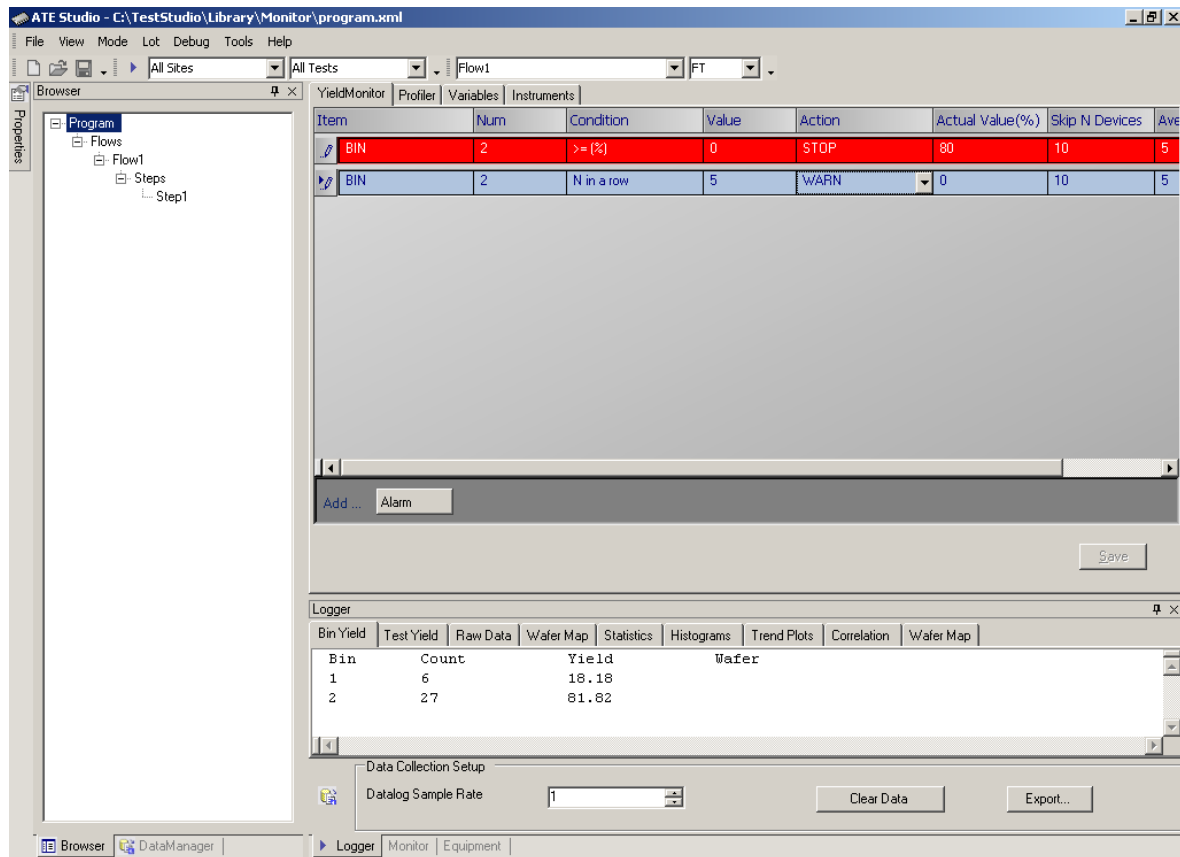
The screen given below displays a warning scenario



FTI Studio automatically resets the GUI whenever the alarm condition disappears.

YIELD MONITOR – ERROR

The screen given below displays an error criteria:



Whenever an error criteria is reached, the Yield Monitor stops testing.

The GUI gets automatically reset whenever the alarm condition disappears in subsequent test executions.